

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Hisae SHIBUYA, et al.

Application No.: 10/672,010

Filed: September 25, 2003

For: METHOD AND APPARATUS FOR
ANALYZING DEFECT DATA AND A
REVIEW SYSTEM

Customer No.: 20350

Confirmation No. 7689

Examiner: Alex Kok Soon Liew

Technology Center/Art Unit: 2624

AMENDMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 16, 2008 (e-filed)

Sir:

In response to the Office Action mailed June 16, 2008, please enter the following amendments and remarks:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 7 of this paper.